

Title:	Performance report for SiT3372, 148.5 MHz, LVPECL		
Type:	Performance report	Rev:	1.2
Orig:		Date:	September 07, 2018

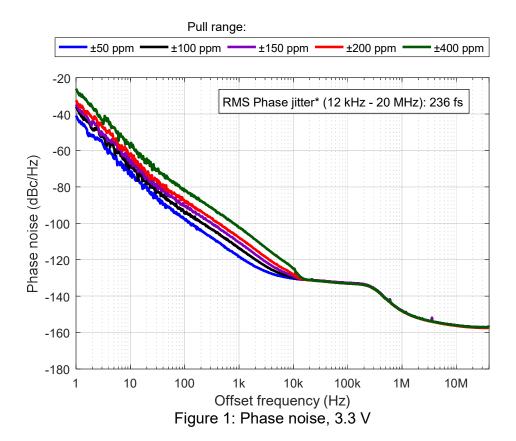
Performance report for SiT3372 - 148.5 MHz, LVPECL

This performance report contains the following data:

- Phase noise
- Random phase jitter
- Output waveforms
- Pull range linearity
- Frequency stability over temperature
- Period jitter
- Duty cycle
- Rise/Fall time
- Amplitude
- Current consumption



Title:	Performance report for SiT3372, 148.5 MHz, LVPECL			
Type:	Performance report Rev: 1.2			
Orig:		Date:	September 07, 2018	



*Integrated phase jitter value applies for ±50 ppm to ±400 ppm pull ranges

Table 1: Phase noise

Phase noise dBc/Hz					
Frequency offset	Pull range (ppm)				
(Hz)	±50	±100	±150	±200	±400
1	-40.9	-35.9	-34.7	-32.4	-26.1
10	-74.0	-69.4	-67.2	-61.6	-57.1
100	-97.8	-93.8	-90.4	-87.7	-81.6
1 K	-118.3	-113.6	-110.6	-107.9	-102.4
10 K	-130.4	-129.8	-129.1	-128.1	-125.0
100 K	-132.8	-132.8	-132.8	-133.1	-133.1
1 M	-147.9	-147.9	-148.0	-148.1	-148.0
10 M	-156.1	-156.1	-156.1	-156.3	-156.0
40 M	-157.0	-156.9	-157.0	-157.4	-157.0

5451 Patrick Henry Drive, Santa Clara, California 95054 • 408.328.4400 • sitime.com

Page 2 of 10



Title:	Performance report for SiT3372, 148.5 MHz, LVPECL		
Type:	Performance report	Rev:	1.2
Orig:		Date:	September 07, 2018

Table 2: Integrated Phase jitter

Parameter	Units	Pull range (ppm)
Parameter	Utills	±50 to ±400
Integrated Phase jitter (1.875 MHz - 20 MHz)	fs, rms	106
Integrated Phase jitter (12 kHz - 20 MHz)	fs, rms	236



Title:	Performance report for SiT3372, 148.5 MHz, LVPECL			
Type:	Performance report Rev: 1.2			
Orig:		Date:	September 07, 2018	



Figure 2: Output waveform, 2.5 V



Figure 3: Output waveform, 3.3 V

5451 Patrick Henry Drive, Santa Clara, California 95054 • 408.328.4400 • sitime.com

Page 4 of 10



Title:	Performance report for SiT3372, 148.5 MHz, LVPECL			
Type:	Performance report Rev: 1.2			
Orig:		Date:	September 07, 2018	

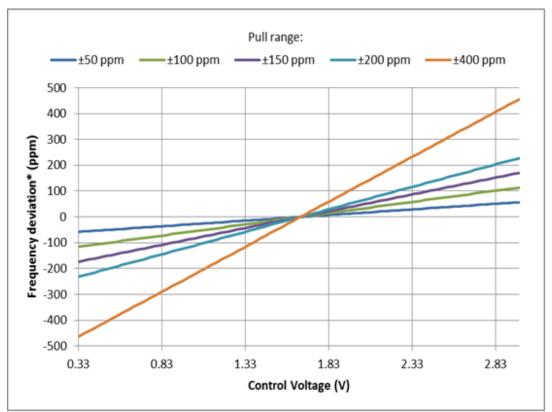


Figure 4: Frequency pull characteristic



Title:	Performance report for SiT3372, 148.5 MHz, LVPECL			
Type:	Performance report Rev: 1.2			
Orig:		Date:	September 07, 2018	

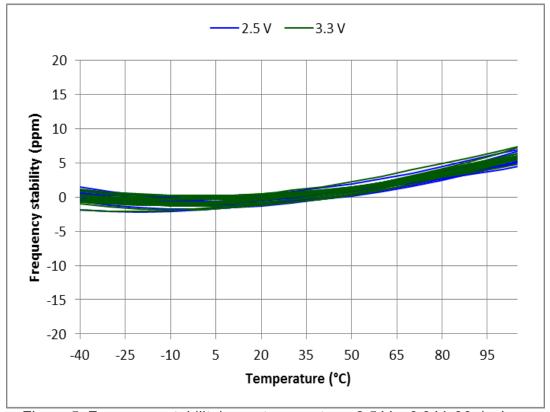


Figure 5: Frequency stability* over temperature, 2.5 V – 3.3 V, 30 devices

*SiT3372 frequency stability is independent of output frequency.



Title:	Performance report for SiT3372, 148.5 MHz, LVPECL		
Type:	Performance report	Rev:	1.2
Orig:		Date:	September 07, 2018

Table 3: Summary performance data

Parameter	Units	Voltage		
Parameter	Utilits	2.5 V	3.3 V	
Period jitter	ps, rms	1.02	1.02	
Period jitter (sample size 10,000 cycles)	ps, pk-pk	7.88	7.83	
Duty cycle	%	50.1	50.1	
Rise time (20% - 80%)	ps	213	202	
Fall time (80% - 20%)	ps	211	201	
Differential voltage swing	V	1.63	1.61	
Current consumption (no load, output enabled)	mA	82.8	83.1	
Current consumption (no load, output disabled)	mA	56.6	56.6	



Title:	Performance report for SiT3372, 148.5 MHz, LVPECL			
Type:	Performance report Rev: 1.2			
Orig:		Date:	September 07, 2018	

Test description

Conditions:

Frequency: 148.5 MHzVDD: 2.5 V, 3.3 V

- Pull range: ±50 ppm, ±100 ppm, ±150 ppm, ±200 ppm, ±400 ppm

- Temperature: 25 °C

Equipment:

Model	Measurement / Purpose
Keysight DSA90604A (6 GHz,	Period jitter, output amplitude, rise/fall time,
20 Gsps)	duty cycle
Keysight 5052B Signal Source	Phase noise, integrated phase jitter
Analyzer	
Keysight 34980A	Power supply current
Keysight E3631A	Power supply
Keysight 53230A	Frequency



Title:	Performance report for SiT3372, 148.5 MHz, LVPECL				
Type:	Performance report	Rev:	1.2		
Orig:		Date:	September 07, 2018		

Setup

Waveform

For waveform parameters measurement (rise/fall time, differential swing, duty cycle), both DUT outputs are terminated with 50 Ω to VDD - 2 V. Output signals are measured using Keysight 1134B active probe with Keysight N5425B probe head. All measurements are applied to the differential waveform. Figure 6 shows test setup diagram for waveform parameters measurement.

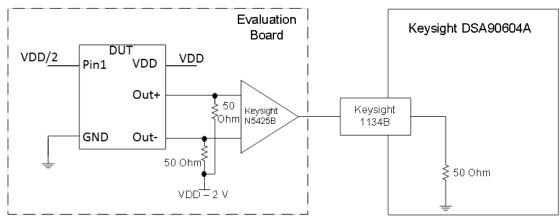


Figure 6. Test setup for measuring waveform parameters (rise/fall time, differential swing, duty cycle)

Period Jitter

For period jitter measurement output is terminated with 50 Ω to VDD – 2 V at the input of hi-speed comparator (ADCMP581). AC coupled comparator's output is connected to oscilloscope channel. Figure 7 shows test setup diagram for period jitter measurement.

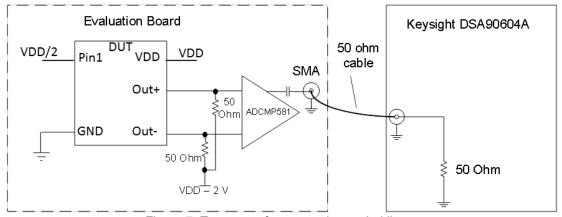


Figure 7. Test setup for measuring period jitter

5451 Patrick Henry Drive, Santa Clara, California 95054 • 408.328.4400 • sitime.com

Page 9 of 10

	Title:	Performance report for SiT3372, 148.5 MHz, LVPECL			
Si Time	Type:	Performance report	Rev:	1.2	
	Orig:		Date:	September 07, 2018	

Phase noise

For phase noise measurements, differential signal is converted to single-ended using impedance matching transformer. Transformer's output is connected to measurement instrument. Figure 8 shows test setup diagram for phase noise measurement.

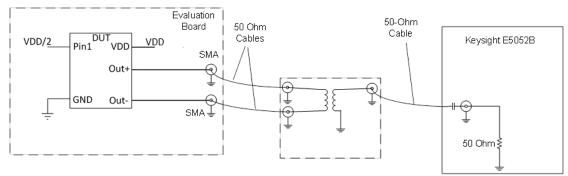


Figure 8. Test setup for measuring phase noise.

Current consumption

For Current consumption measurement device output is floating. For frequency measurement differential-to-single-ended converter is used.